

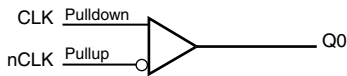
General Description

The 83021I is a 1-to-1 Differential-to-LVCMOS/ LVTTL Translator and a member of the family of High Performance Clock Solutions from IDT. The differential input is highly flexible and can accept the following input types: LVPECL, LVDS, LVHSTL, SSTL, and HCSL. The small 8-lead SOIC footprint makes this device ideal for use in applications with limited board space.

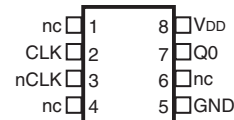
Features

- One LVCMOS/LVTTL output
- Differential CLK/nCLK input pair
- CLK/nCLK pair can accept the following differential input levels: LVPECL, LVDS, LVHSTL, SSTL, HCSL
- Output frequency: 350MHz (typical)
- Part-to-part skew: 500ps (maximum)
- Additive phase jitter, RMS: 0.21ps (typical), 3.3V output
- Full 3.3V and 2.5V operating supply
- -40°C to 85°C ambient operating temperature

Block Diagram



Pin Assignment



83021I

8-Lead SOIC, 150Mil

3.9mm x 4.9mm x 1.375mm package body

M Package

Top View

Table 1. Pin Descriptions

Number	Name	Type		Description
1, 4, 6	nc	Unused		No connect.
2	CLK	Input	Pulldown	Non-inverting differential clock input.
3	nCLK	Input	Pullup	Inverting differential clock input.
5	GND	Power		Power supply ground.
7	Q0	Output		Single-ended clock output. LVCMOS/LVTTL interface levels.
8	V _{DD}	Power		Positive supply pin.

NOTE: *Pullup and Pulldown* refer to internal input resistors. See Table 2, *Pin Characteristics*, for typical values.

Table 2. Pin Characteristics

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
C _{IN}	Input Capacitance			4		pF
R _{PULLUP}	Input Pullup Resistor			51		kΩ
R _{PULLDOWN}	Input Pulldown Resistor			51		kΩ
C _{PD}	Power Dissipation Capacitance	V _{DD} = 3.6V		23		pF
R _{OUT}	Output Impedance		5	7	12	Ω

Absolute Maximum Ratings

NOTE: Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These ratings are stress specifications only. Functional operation of product at these conditions or any conditions beyond those listed in the *DC Characteristics* or *AC Characteristics* is not implied. Exposure to absolute maximum rating conditions for extended periods may affect product reliability.

Item	Rating
Supply Voltage, V_{DD}	4.6V
Inputs, V_I	-0.5V to $V_{DD} + 0.5V$
Outputs, V_O	-0.5V to $V_{DD} + 0.5V$
Package Thermal Impedance, θ_{JA}	103°C/W (0 lfpm)
Storage Temperature, T_{STG}	-65°C to 150°C

DC Electrical Characteristics

Table 3A. Power Supply DC Characteristics, $V_{DD} = 3.3V \pm 0.3V$ or $2.5V \pm 5\%$, $T_A = -40^\circ C$ to $85^\circ C$

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V_{DD}	Positive Supply Voltage		3.0	3.3	3.6	V
			2.375	2.5	2.625	V
I_{DD}	Power Supply Current				20	mA

Table 3B. LVCMOS/LVTTL DC Characteristics, $V_{DD} = 3.3V \pm 0.3V$ or $2.5V \pm 5\%$, $T_A = -40^\circ C$ to $85^\circ C$

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V_{OH}	Output High Voltage; NOTE 1	$V_{DD} = 3.6V$	2.6			V
		$V_{DD} = 2.625V$	1.8			V
V_{OL}	Output Low Voltage; NOTE 1	$V_{DD} = 3.6V$ or $2.625V$			0.5	V

NOTE 1: Outputs terminated with 50Ω to $V_{DD}/2$. See Parameter Measurement Information, *Output Load Test Circuit Diagrams*.

Table 3C. Differential DC Characteristics, $V_{DD} = 3.3V \pm 0.3V$ or $2.5V \pm 5\%$, $T_A = -40^\circ C$ to $85^\circ C$

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
I_{IH}	Input High Current	nCLK $V_{IN} = V_{DD} = 3.6V$ or $2.625V$			5	μA
		CLK $V_{IN} = V_{DD} = 3.6V$ or $2.625V$			150	μA
I_{IL}	Input Low Current	nCLK $V_{IN} = 0V$, $V_{DD} = 3.6V$ or $2.625V$	-150			μA
		CLK $V_{IN} = 0V$, $V_{DD} = 3.6V$ or $2.625V$	-5			μA
V_{PP}	Peak-to-Peak Input Voltage		0.15		1.3	V
V_{CMR}	Common Mode Input Voltage; NOTE 1, 2		GND + 0.5		$V_{DD} - 0.85$	V

NOTE 1: For single ended applications, the maximum input voltage for CLK, nCLK is $V_{DD} + 0.3V$.

NOTE 2: Common mode voltage is defined as V_{IH} .

AC Electrical Characteristics

Table 4A. AC Characteristics, $V_{DD} = 3.3V \pm 0.3V$, $T_A = -40^{\circ}C$ to $85^{\circ}C$

Parameter	Symbol	Test Conditions	Minimum	Typical	Maximum	Units
f_{MAX}	Output Frequency			350		MHz
t_{PD}	Propagation Delay, NOTE 1	$f \leq 350MHz$	1.7	2.0	2.3	ns
$t_{sk(pp)}$	Part-to-Part Skew; NOTE 2, 3				500	ps
t_{jit}	Buffer Additive Phase Jitter, RMS; refer to Additive Phase Jitter Section	100MHz, Integration Range (637kHz – 10MHz)		0.21		ps
t_R / t_F	Output Rise/Fall Time	0.8V to 2V	100	250	400	ps
odc	Output Duty Cycle	$f \leq 166MHz$	45	50	55	%
		$166MHz < f \leq 350MHz$	40	50	60	%

NOTE: Electrical parameters are guaranteed over the specified ambient operating temperature range, which is established when the device is mounted in a test socket with maintained transverse airflow greater than 500 lfpm. The device will meet specifications after thermal equilibrium has been reached under these conditions.

All parameters measured at f_{MAX} unless noted otherwise.

NOTE 1: Measured from the differential input crossing point to the output at $V_{DD}/2$.

NOTE 2: Defined as skew between outputs on different devices operating at the same supply voltage and with equal load conditions. Using the same type of inputs on each device, the outputs are measured at $V_{DD}/2$.

NOTE 3: This parameter is defined in accordance with JEDEC Standard 65.

Table 4B. AC Characteristics, $V_{DD} = 2.5V \pm 5\%$, $T_A = -40^{\circ}C$ to $85^{\circ}C$

Parameter	Symbol	Test Conditions	Minimum	Typical	Maximum	Units
f_{MAX}	Output Frequency			350		MHz
t_{PD}	Propagation Delay, NOTE 1	$f \leq 350MHz$	1.9	2.2	2.5	ns
$t_{sk(pp)}$	Part-to-Part Skew; NOTE 2, 3				500	ps
t_{jit}	Buffer Additive Phase Jitter, RMS; refer to Additive Phase Jitter Section	100MHz, Integration Range (637kHz – 10MHz)		0.21		ps
t_R / t_F	Output Rise/Fall Time	20% to 80%	250		550	ps
odc	Output Duty Cycle	$f \leq 250MHz$	45	50	55	%
		$250MHz < f \leq 350MHz$	40	50	60	%

NOTE: Electrical parameters are guaranteed over the specified ambient operating temperature range, which is established when the device is mounted in a test socket with maintained transverse airflow greater than 500 lfpm. The device will meet specifications after thermal equilibrium has been reached under these conditions.

All parameters measured at f_{MAX} unless noted otherwise.

NOTE 1: Measured from the differential input crossing point to the output at $V_{DD}/2$.

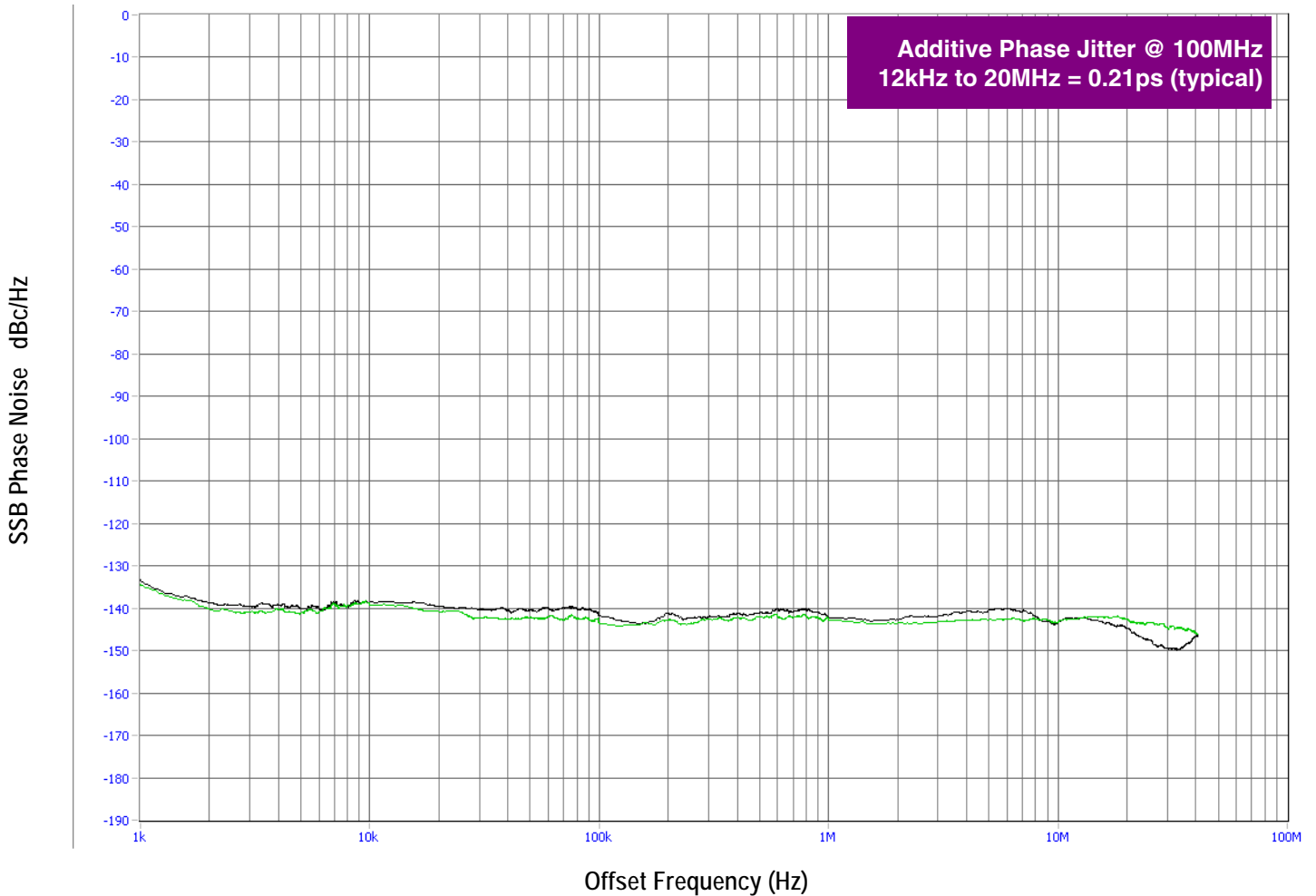
NOTE 2: Defined as skew between outputs on different devices operating at the same supply voltage and with equal load conditions. Using the same type of inputs on each device, the outputs are measured at $V_{DD}/2$.

NOTE 3: This parameter is defined in accordance with JEDEC Standard 65.

Additive Phase Jitter

The spectral purity in a band at a specific offset from the fundamental compared to the power of the fundamental is called the ***dBc Phase Noise***. This value is normally expressed using a Phase noise plot and is most often the specified plot in many applications. Phase noise is defined as the ratio of the noise power present in a 1Hz band at a specified offset from the fundamental frequency to the power value of the fundamental. This ratio is expressed in decibels (dBm) or a ratio of the power in the 1Hz band

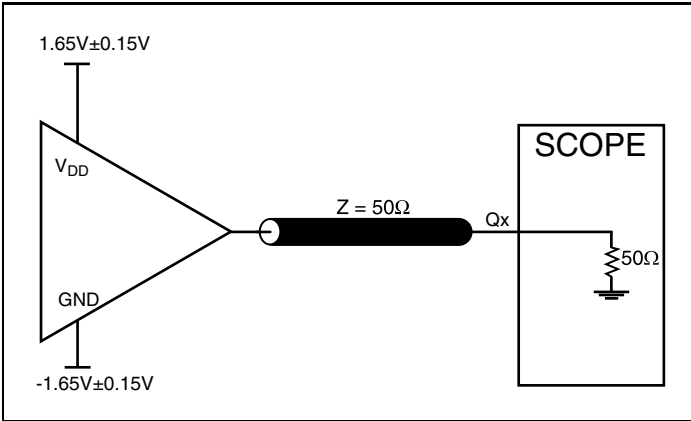
to the power in the fundamental. When the required offset is specified, the phase noise is called a ***dBc*** value, which simply means dBm at a specified offset from the fundamental. By investigating jitter in the frequency domain, we get a better understanding of its effects on the desired application over the entire time record of the signal. It is mathematically possible to calculate an expected bit error rate given a phase noise plot.



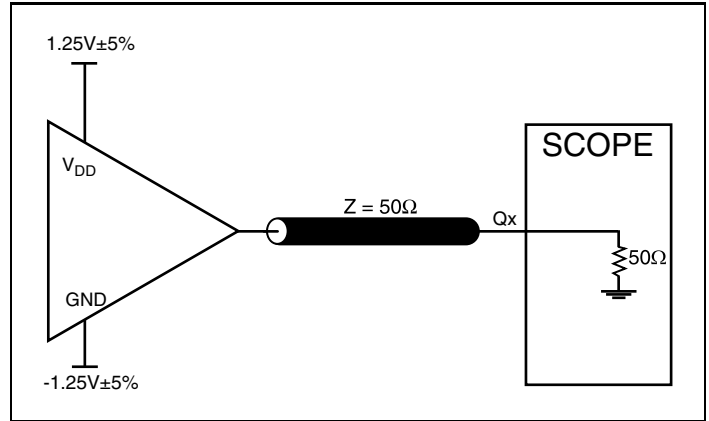
As with most timing specifications, phase noise measurements has issues relating to the limitations of the equipment. Often the noise floor of the equipment is higher than the noise floor of the

device. This is illustrated above. The device meets the noise floor of what is shown, but can actually be lower. The phase noise is dependent on the input source and measurement equipment.

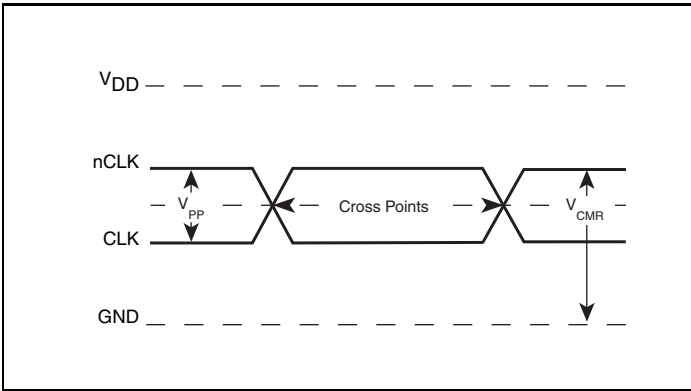
Parameter Measurement Information



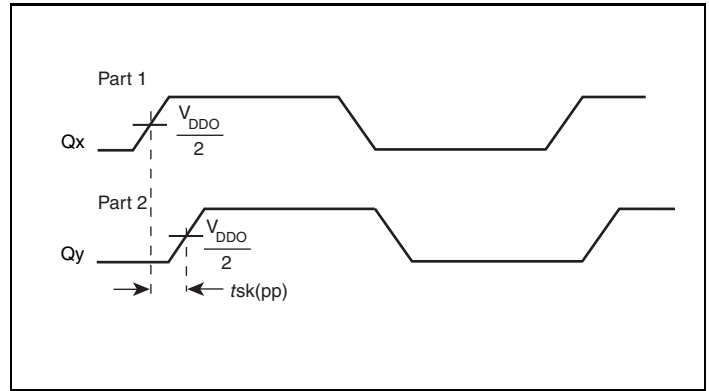
3.3V Core/3.3V LVCMOS Output Load AC Test Circuit



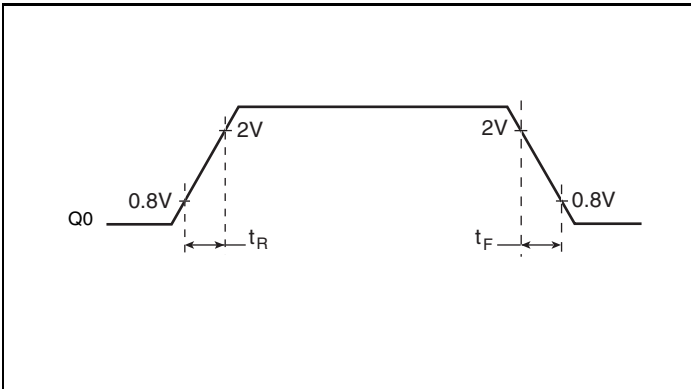
2.5V Core/2.5V LVCMOS Output Load AC Test Circuit



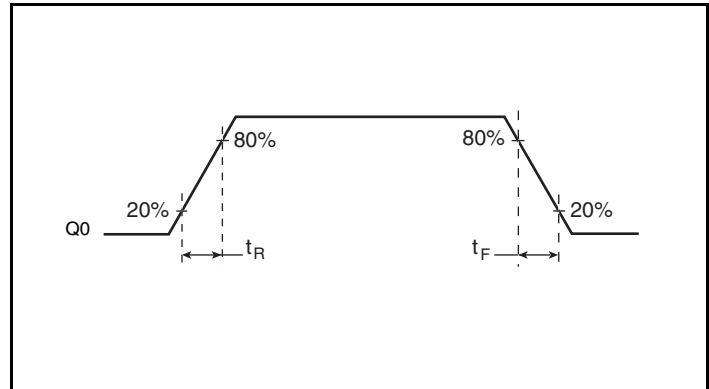
Differential Input Level



Part-to-Part Skew

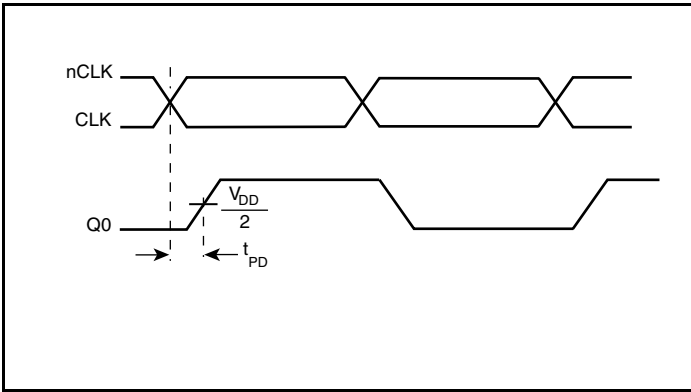


3.3V Output Rise/Fall Time

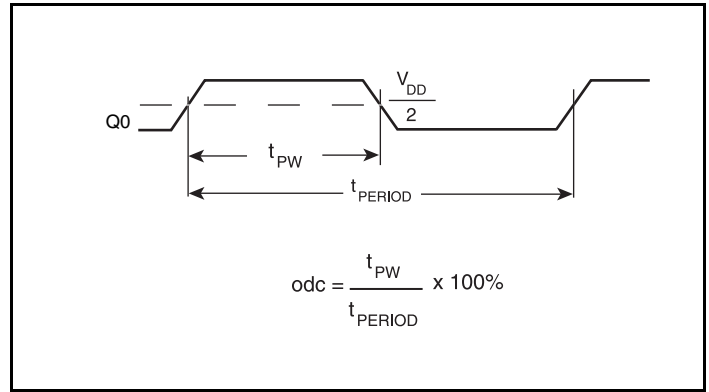


2.5V Output Rise/Fall Time

Parameter Measurement Information, continued



Propagation Delay



Output Duty Cycle/Pulse Width/Period

Application Information

Wiring the Differential Input to Accept Single Ended Levels

Figure 1 shows how the differential input can be wired to accept single ended levels. The reference voltage $V_REF = V_{DD}/2$ is generated by the bias resistors R1, R2 and C1. This bias circuit should be located as close as possible to the input pin. The ratio of R1 and R2 might need to be adjusted to position the V_REF in the center of the input voltage swing. For example, if the input clock swing is only 2.5V and $V_{DD} = 3.3V$, V_REF should be 1.25V and $R2/R1 = 0.609$.

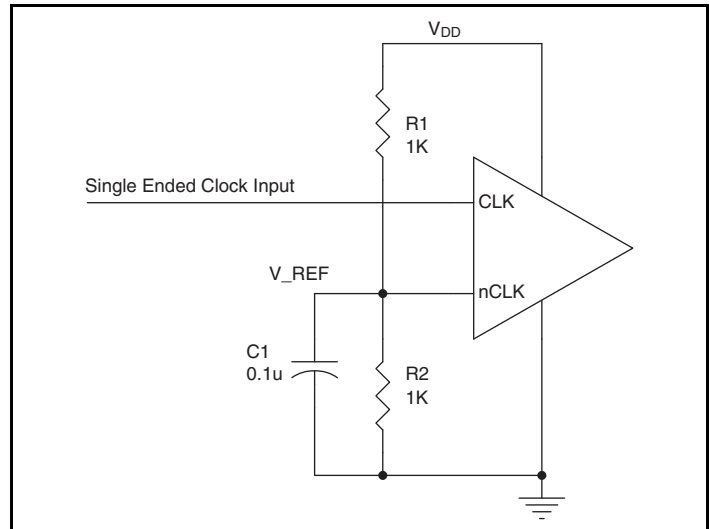


Figure 1. Single-Ended Signal Driving Differential Input

Differential Clock Input Interface

The CLK /nCLK accepts LVDS, LVPECL, LVHSTL, SSTL, HCSL and other differential signals. Both signals must meet the V_{PP} and V_{CMR} input requirements. Figures 2A to 2F show interface examples for the HiPerClockS CLK/nCLK input driven by the most common driver types. The input interfaces suggested here are examples only. Please consult with the vendor of the driver

component to confirm the driver termination requirements. For example, in Figure 2A, the input termination applies for IDT HiPerClockS open emitter LVHSTL drivers. If you are using an LVHSTL driver from another vendor, use their termination recommendation.

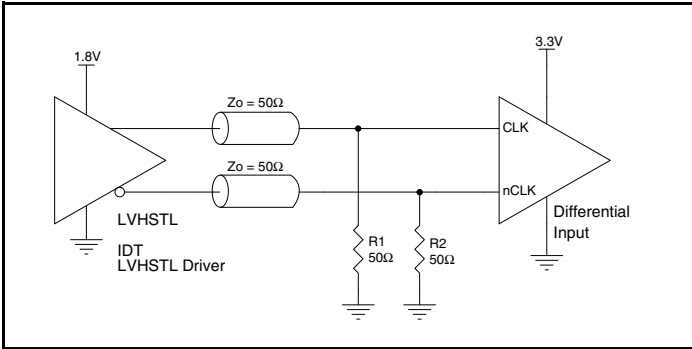


Figure 2A. HiPerClockS CLK/nCLK Input Driven by an IDT Open Emitter HiPerClockS LVHSTL Driver

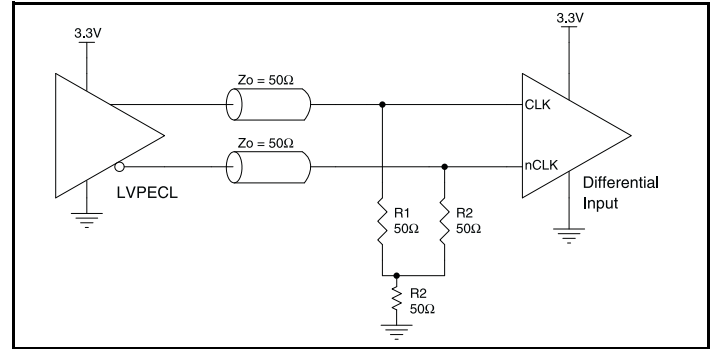


Figure 2B. HiPerClockS CLK/nCLK Input Driven by a 3.3V LVPECL Driver

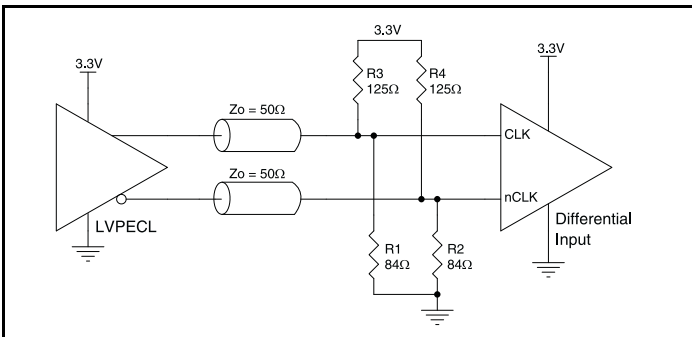


Figure 2C. HiPerClockS CLK/nCLK Input Driven by a 3.3V LVPECL Driver

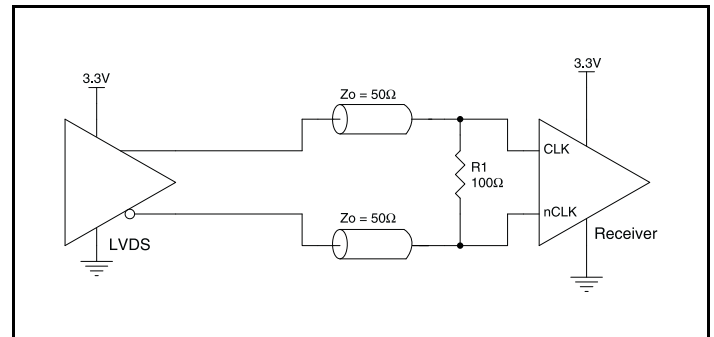


Figure 2D. HiPerClockS CLK/nCLK Input Driven by a 3.3V LVDS Driver

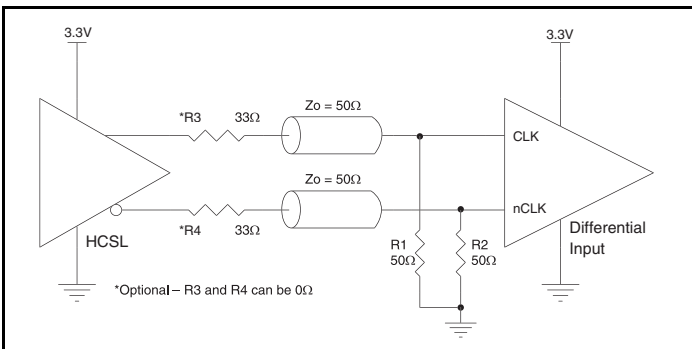


Figure 2E. HiPerClockS CLK/nCLK Input Driven by a 3.3V HCSL Driver

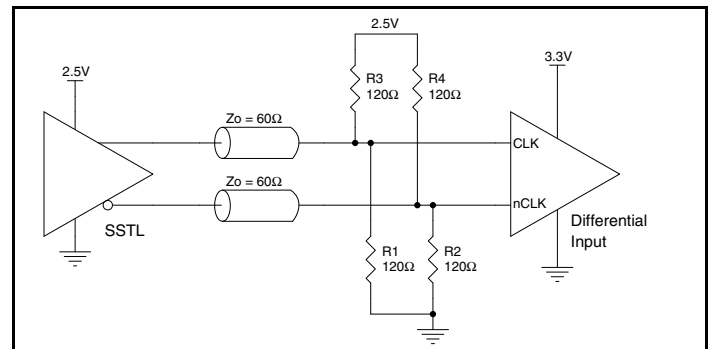


Figure 2F. HiPerClockS CLK/nCLK Input Driven by a 2.5V SSTL Driver

Reliability Information

Table 5. θ_{JA} vs. Air Flow Table for an 8 Lead SOIC

Linear Feet per Minute	θ_{JA} by Velocity		
	0	200	500
Single-Layer PCB, JEDEC Standard Test Boards	123°C/W	110°C/W	99°C/W
Multi-Layer PCB, JEDEC Standard Test Boards	103°C/W	94°C/W	89°C/W

Transistor Count

The transistor count for 830211 is: 416
 Pin-to-pin compatible with the MC100EPT21

Package Outline and Package Dimensions

Package Outline - M Suffix for 8 Lead SOIC

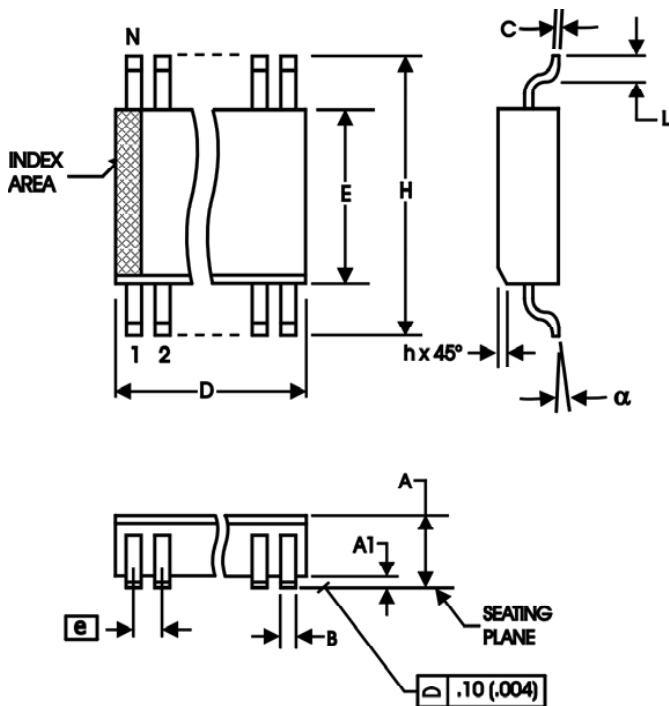


Table 6. Package Dimensions

All Dimensions in Millimeters		
Symbol	Minimum	Maximum
N	8	
A	1.35	1.75
A1	0.10	0.25
B	0.33	0.51
C	0.19	0.25
D	4.80	5.00
E	3.80	4.00
e	1.27 Basic	
H	5.80	6.20
h	0.25	0.50
L	0.40	1.27
α	0°	8°

Reference Document: JEDEC Publication 95, MS-012

Ordering Information

Table 7. Ordering Information

Part/Order Number	Marking	Package	Shipping Packaging	Temperature
83021AMILF	83021AIL	“Lead-Free” 8 Lead SOIC	Tube	-40°C to 85°C
83021AMILFT	83021AIL	“Lead-Free” 8 Lead SOIC	Tape & Reel	-40°C to 85°C

Revision History Sheet

Rev	Table	Page	Description of Change	Date	
B	T2	2	Pin Characteristics table - added 2.5V C_{PD} .	6/3/04	
	T3B	3	Added 2.5V Power Supply table.		
	T3C	3	LVC MOS table - added 2.5V V_{OH} .		
	T3D	3	Differential table - added 2.5V.		
	T4B	4	Added 2.5V AC Characteristics table.		
		5	Added 2.5V Output Load AC Test Circuit Diagram, and 2.5V Output Rise/Fall Time Diagrams.		
		6	Updated Figure 1.		
		7	Added Differential Clock Input Interface section.		
B	T4A	2	Pin Characteristics Table - changed C_{IN} 4pF max. to 4pF typical.	6/30/04	
		4	3.3V AC Characteristics Table - changed odc Test Conditions.		
B	T7	1	Features Section - added Lead-Free bullet.	3/21/05	
		10	Ordering Information Table - Added Lead-Free part number.		
C	T4A, T4B	1	Features Section - added Additive Phase Jitter bullet.	12/12/05	
		4	AC Characteristics Tables - added Additive Phase Jitter row.		
	5	Added Additive Phase Jitter Plot.			
	11	Added Lead-Free Note.			
C		1	Pin Assignment - corrected package body measurements.	6/18/08	
		8	Updated <i>Differential Clock Input Interface</i> .		
		9	Updated <i>Reliability Information</i> . Updated datasheet format .		
C	T4A, T4B	1	Corrected typo in Header from 1-to-2... to 1-to-1....	10/31/08	
		4	AC Tables - added Temperature NOTE.		
D	T7	10	Remove leaded orderable parts from Ordering Information table	11/14/12	
D		1	Features section - removed leaded part note.	4/23/14	
			Description - removed chip		
D	T7	1	Removed HiPerClockS from General Description.	12/14/15	
			10		Ordering Information - removed 2500 from Tape and Reel.
			Updated Datasheet header and footer.		

Notice

1. Descriptions of circuits, software and other related information in this document are provided only to illustrate the operation of semiconductor products and application examples. You are fully responsible for the incorporation or any other use of the circuits, software, and information in the design of your product or system. Renesas Electronics disclaims any and all liability for any losses and damages incurred by you or third parties arising from the use of these circuits, software, or information.
 2. Renesas Electronics hereby expressly disclaims any warranties against and liability for infringement or any other claims involving patents, copyrights, or other intellectual property rights of third parties, by or arising from the use of Renesas Electronics products or technical information described in this document, including but not limited to, the product data, drawings, charts, programs, algorithms, and application examples.
 3. No license, express, implied or otherwise, is granted hereby under any patents, copyrights or other intellectual property rights of Renesas Electronics or others.
 4. You shall not alter, modify, copy, or reverse engineer any Renesas Electronics product, whether in whole or in part. Renesas Electronics disclaims any and all liability for any losses or damages incurred by you or third parties arising from such alteration, modification, copying or reverse engineering.
 5. Renesas Electronics products are classified according to the following two quality grades: "Standard" and "High Quality". The intended applications for each Renesas Electronics product depends on the product's quality grade, as indicated below.
 - "Standard": Computers; office equipment; communications equipment; test and measurement equipment; audio and visual equipment; home electronic appliances; machine tools; personal electronic equipment; industrial robots; etc.
 - "High Quality": Transportation equipment (automobiles, trains, ships, etc.); traffic control (traffic lights); large-scale communication equipment; key financial terminal systems; safety control equipment; etc.Unless expressly designated as a high reliability product or a product for harsh environments in a Renesas Electronics data sheet or other Renesas Electronics document, Renesas Electronics products are not intended or authorized for use in products or systems that may pose a direct threat to human life or bodily injury (artificial life support devices or systems; surgical implantations; etc.), or may cause serious property damage (space system; undersea repeaters; nuclear power control systems; aircraft control systems; key plant systems; military equipment; etc.). Renesas Electronics disclaims any and all liability for any damages or losses incurred by you or any third parties arising from the use of any Renesas Electronics product that is inconsistent with any Renesas Electronics data sheet, user's manual or other Renesas Electronics document.
 6. When using Renesas Electronics products, refer to the latest product information (data sheets, user's manuals, application notes, "General Notes for Handling and Using Semiconductor Devices" in the reliability handbook, etc.), and ensure that usage conditions are within the ranges specified by Renesas Electronics with respect to maximum ratings, operating power supply voltage range, heat dissipation characteristics, installation, etc. Renesas Electronics disclaims any and all liability for any malfunctions, failure or accident arising out of the use of Renesas Electronics products outside of such specified ranges.
 7. Although Renesas Electronics endeavors to improve the quality and reliability of Renesas Electronics products, semiconductor products have specific characteristics, such as the occurrence of failure at a certain rate and malfunctions under certain use conditions. Unless designated as a high reliability product or a product for harsh environments in a Renesas Electronics data sheet or other Renesas Electronics document, Renesas Electronics products are not subject to radiation resistance design. You are responsible for implementing safety measures to guard against the possibility of bodily injury, injury or damage caused by fire, and/or danger to the public in the event of a failure or malfunction of Renesas Electronics products, such as safety design for hardware and software, including but not limited to redundancy, fire control and malfunction prevention, appropriate treatment for aging degradation or any other appropriate measures. Because the evaluation of microcomputer software alone is very difficult and impractical, you are responsible for evaluating the safety of the final products or systems manufactured by you.
 8. Please contact a Renesas Electronics sales office for details as to environmental matters such as the environmental compatibility of each Renesas Electronics product. You are responsible for carefully and sufficiently investigating applicable laws and regulations that regulate the inclusion or use of controlled substances, including without limitation, the EU RoHS Directive, and using Renesas Electronics products in compliance with all these applicable laws and regulations. Renesas Electronics disclaims any and all liability for damages or losses occurring as a result of your noncompliance with applicable laws and regulations.
 9. Renesas Electronics products and technologies shall not be used for or incorporated into any products or systems whose manufacture, use, or sale is prohibited under any applicable domestic or foreign laws or regulations. You shall comply with any applicable export control laws and regulations promulgated and administered by the governments of any countries asserting jurisdiction over the parties or transactions.
 10. It is the responsibility of the buyer or distributor of Renesas Electronics products, or any other party who distributes, disposes of, or otherwise sells or transfers the product to a third party, to notify such third party in advance of the contents and conditions set forth in this document.
 11. This document shall not be reprinted, reproduced or duplicated in any form, in whole or in part, without prior written consent of Renesas Electronics.
 12. Please contact a Renesas Electronics sales office if you have any questions regarding the information contained in this document or Renesas Electronics products.
- (Note1) "Renesas Electronics" as used in this document means Renesas Electronics Corporation and also includes its directly or indirectly controlled subsidiaries.
- (Note2) "Renesas Electronics product(s)" means any product developed or manufactured by or for Renesas Electronics.

(Rev.4.0-1 November 2017)

Corporate Headquarters

TOYOSU FORESIA, 3-2-24 Toyosu,
Koto-ku, Tokyo 135-0061, Japan
www.renesas.com

Contact Information

For further information on a product, technology, the most up-to-date version of a document, or your nearest sales office, please visit:
www.renesas.com/contact/

Trademarks

Renesas and the Renesas logo are trademarks of Renesas Electronics Corporation. All trademarks and registered trademarks are the property of their respective owners.